Search Notes

Application/Control	

Applicant(s)/Patent Reexamination	under

10/799,694 Examiner

Binh V. Ho

MURAKATA ET AL.
Art Unit

2821

SEARCHED			
Class	Subclass	Date	Examiner
315	169.3	12/7/2005	вн

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
343	169.3	10/7/2005	вн
315	169.1	12/7/2005	ВН
	-		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
315/169.1,169.2,169.4;345/76,78,84,9 1,36 East search (see printout)	12/7/2005	вн
315/169.1,169.2,169.4;345/76,78,84,9 1,36 (US Pub search)	12/7/2005	вн
East seach (Inventors)	12/7/2005	вн
Consulted Trinh (Primary 315) - search, claims	12/7/2005	вн